NOTES:

- 1. SUBSTRATE: Fused Silica
- 2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN <3 ARCMIN
- 3. COATING (APPLY ACROSS CLEAR APERTURE)

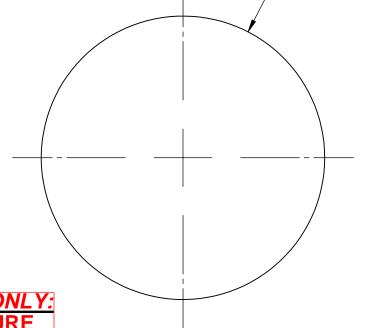
S1: R(ABS) >99.5% @ 532 & 1064nm @ 45° AOI DAMAGE THRESHOLD:

15 J/cm2 @ 20ns @ 532nm 20 J/cm2 @ 20ns @ 1064nm

S2: NONE

4. COMMERCIAL POLISHED

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATION APPLY ACROSS CLEAR APERTURE

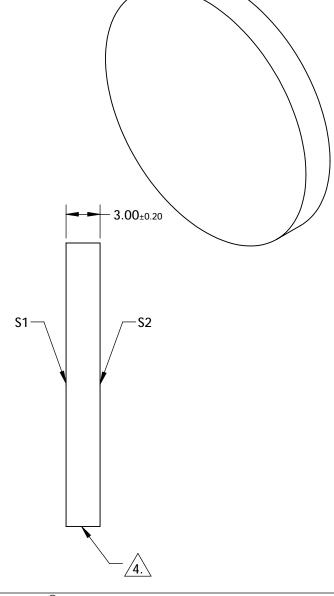


 \emptyset 25.00 $^{0.00}_{-0.20}$

FOR INFORMATION ONLY: DO NOT MANUFACTURE PARTS TO THIS DRAWING

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE DIMENSIONS ARE FOR REFERENCE ONLY

	S1	S2	
SHAPE	PLANO	PLANO	
SURFACE QUALITY	10-5	NA	
CLEAR APERTURE	Ø22.5	NA	
BEVEL	PROTECTED AS NEEDED	PROTECTED AS NEEDED	



A	Edmund	Optics®

-			-		
_	THIRD ANGLE _ PROJECTION	$\phi \lhd$	TITLE	25mm Dia. x 3mm 532/1064nm, Dual E Laser Mirror	Band
	ALL DIMS IN	mm	DWG NO	20216	SHEET